

**Notice of References Cited**

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Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

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Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,570,597 B1	05-2003	Seki et al.	345/835
	B	US-6,141,659 A	10-2000	Barker et al.	707/102
	C	US-5,748,931	05-1998	Jones et al.	1/1
	D	US-6,275,829 B1	08-2001	Angiulo et al.	707/104.1
	E	US-6,073,136 A	06-2000	Bertram et al.	707/104.1
	F	US-6,275,229 B1	08-2001	Weiner et al.	345/764
	G	US-6,369,820 B1	04-2002	Bertram et al.	345/440
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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A.R.